

OKI Semiconductor

MSM511002B

1,048,576-Word × 1-Bit DYNAMIC RAM: STATIC COLUMN MODE TYPE

DESCRIPTION

The MSM511002B is a new generation dynamic RAM organized as 1,048,576-word × 1-bit. The technology used to fabricate the MSM511002B is OKI's CMOS silicon gate process technology. The device operates at a single 5V power supply. Its I/O pins are TTL compatible.

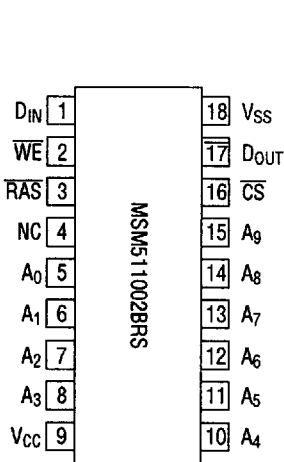
FEATURES

- Silicon gate, quadruple polysilicon CMOS, 1-transistor memory cell
- 1,048,576-word × 1-bit organization
- Signal 5V power supply, ±10% tolerance
- Input: TTL compatible
- Output: TTL compatible, tristate
- Refresh: 512 cycles/8ms
- Common I/O capability using Early Write operation
- Static column mode, read modify write capability
- $\overline{CS}$ before $\overline{RAS}$ refresh, Hidden refresh, $\overline{RAS}$ -only refresh capability
- Package:
 - 18-Pin 300mil Plastic DIP (DIP18-P-300-W1)
 - 26-Pin 300mil Plastic SOJ (SOJ26-P-300)
 - 20-Pin 400mil Plastic ZIP (ZIP20-P-400)

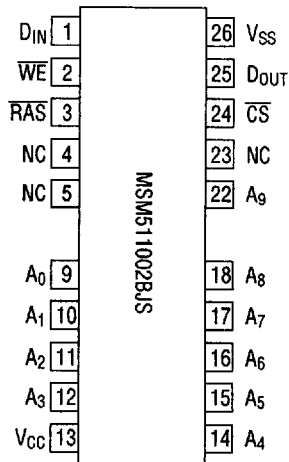
PRODUCT FAMILY

Family	Access Time (Max.)			Cycle Time (Min.)	Power Dissipation	
	t _{RAC}	t _{AA}	t _{CAC}		Operating (Max.)	Standby (Max.)
MSM511002B-60	60ns	30ns	15ns	120ns	495mW	5.5mW
MSM511002B-70	70ns	35ns	20ns	130ns	440mW	
MSM511002B-80	80ns	40ns	20ns	150ns	385mW	
MSM511002B-10	100ns	50ns	25ns	190ns	330mW	

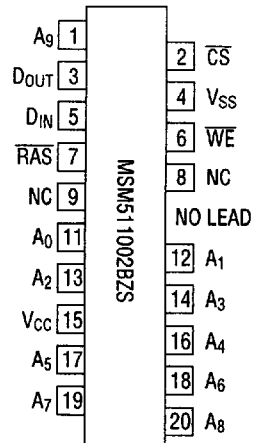
PIN CONFIGURATION (TOP VIEW)



18-PIN DIP



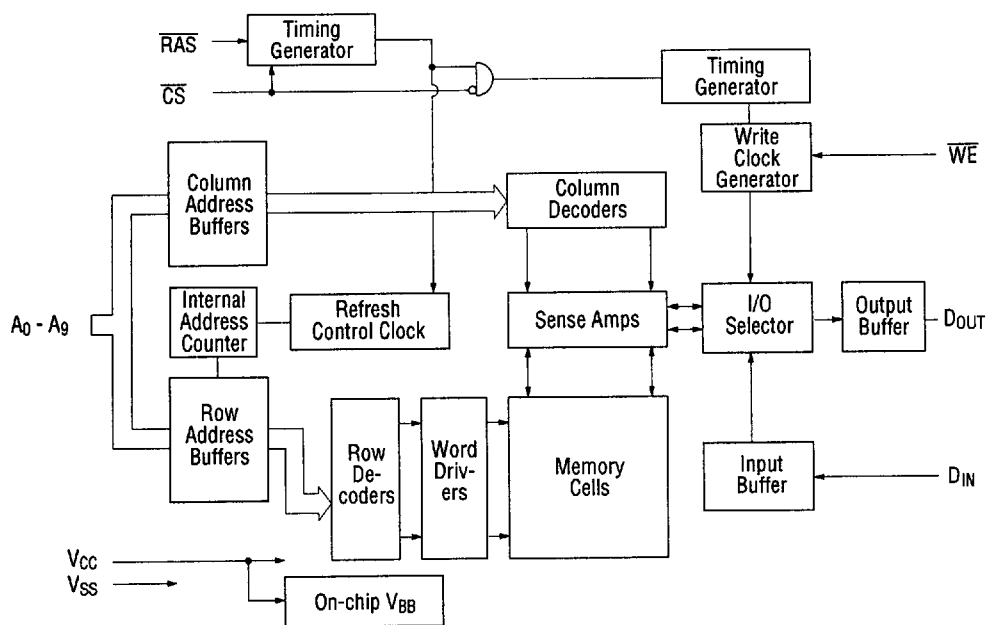
26-PIN SOJ



20-PIN ZIP

Pin Name	Function
A ₀ - A ₉	Address Input
RAS	Row Address Strobe
CS	Chip Select Input
D _{IN}	Data Input
D _{OUT}	Data Output
WE	Write Enable
V _{CC}	Power Supply (5V)
V _{SS}	Ground (0V)
NC	No Connection

FUNCTIONAL BLOCK DIAGRAM



ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings

Parameter	Symbol	Rating	Unit
Voltage on Any Pin Relative to V_{SS}	V_T	-1.0 to 7.0	V
Short Circuit Output Current	I_{OS}	50	mA
Power Dissipation	P_D^*	1	W
Operating Temperature	T_{opr}	0 to 70	°C
Storage Temperature	T_{stg}	-55 to 150	°C

*: $T_a = 25^\circ\text{C}$

Recommended Operating Conditions

 $(T_a = 0 \text{ to } 70^\circ\text{C})$

Parameter	Symbol	Min.	Typ.	Max.	Unit
Power Supply Voltage	V_{CC}	4.5	5.0	5.5	V
	V_{SS}	0	0	0	V
Input High Voltage	V_{IH}	2.4	—	6.5	V
Input Low Voltage	V_{IL}	-1.0	—	0.8	V

Capacitance

 $(V_{CC} = 5V \pm 10\%, T_a = 25^\circ\text{C}, f = 1\text{MHz})$

Parameter	Symbol	Typ.	Max.	Unit
Input Capacitance ($A_0 - A_9, D_{IN}$)	C_{IN1}	—	6	pF
Input Capacitance (RAS, CS, WE)	C_{IN2}	—	7	pF
Output Capacitance (D_{OUT})	C_{OUT}	—	7	pF

DC Characteristics

(V_{CC} = 5V ± 10%, T_a = 0 to 70°C)

Parameter	Symbol	Condition	MSM 511002B-60		MSM 511002B-70		MSM 511002B-80		MSM 511002B-10		Unit	Note
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Output High Voltage	V _{OH}	I _{OH} = 5.0mA	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	V	
Output Low Voltage	V _{OL}	I _{OL} = 4.2mA	0	0.4	0	0.4	0	0.4	0	0.4	V	
Input Leakage Current	I _{LI}	0V ≤ V _I ≤ 6.5V; All other pins not under test = 0V	-10	10	-10	10	-10	10	-10	10	μA	
Output Leakage Current	I _{LO}	DOUT disable 0V ≤ V _O ≤ 5.5V	-10	10	-10	10	-10	10	-10	10	μA	
Average Power Supply Current (Operating)	I _{CC1}	RAS, $\overline{\text{CS}}$ cycling t _{RC} = Min.	—	90	—	80	—	70	—	60	mA	1, 2
Power Supply Current (Standby)	I _{CC2}	RAS, $\overline{\text{CS}}$ = V _{IH}	—	2	—	2	—	2	—	2	mA	1
		RAS, $\overline{\text{CS}}$ = V _{CC} - 0.2V	—	1	—	1	—	1	—	1	mA	1
Average Power Supply Current (RAS-only Refresh)	I _{CC3}	RAS cycling, $\overline{\text{CS}}$ = V _{IH} t _{RC} = Min.	—	90	—	80	—	70	—	60	mA	1, 2
Average Power Supply Current ($\overline{\text{CS}}$ Before RAS Refresh)	I _{CC6}	RAS cycling, $\overline{\text{CS}}$ before RAS refresh	—	90	—	80	—	70	—	60	mA	1
Average Power Supply Current (Static Column Mode)	I _{CC9}	RAS = V _{IL} $\overline{\text{CS}}$ cycling, t _{SC} = Min.	—	80	—	70	—	60	—	55	mA	1

- Notes: 1. Specified values are obtained with the output open.
 2. Address can be changed less than three times while $\overline{\text{RAS}} = V_{IL}$

AC Characteristics (1/3)

(V_{CC} = 5V ± 10%, T_a = 0 to 70°C) Note 1, 2, 3

Parameter	Symbol	MSM 511002B-60		MSM 511002B-70		MSM 511002B-80		MSM 511002B-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Refresh Period	t _{REF}	—	8	—	8	—	8	—	8	ms	
Random Read or Write Cycle Time	t _{RC}	120	—	130	—	150	—	190	—	ns	
Read Modify Write Cycle Time	t _{RMW}	140	—	155	—	175	—	220	—	ns	
Static Column Mode Cycle Time	t _{SC}	40	—	45	—	50	—	55	—	ns	
Static Column Mode Read Modify Write Cycle Time	t _{SRMW}	65	—	70	—	80	—	100	—	ns	
Access Time from RAS	t _{RAC}	—	60	—	70	—	80	—	100	ns	4, 5, 6
Access Time from CS	t _{CAC}	—	15	—	20	—	20	—	25	ns	4, 5
Access Time from Column Address	t _{AA}	—	30	—	35	—	40	—	50	ns	4, 6, 7
Access Time from Last Write	t _{ALW}	—	60	—	65	—	75	—	95	ns	4, 7
Output Low Impedance Time from CS	t _{CLZ}	0	—	0	—	0	—	0	—	ns	
Data Output Hold Time Reference to Column Address	t _{AOH}	5	—	5	—	5	—	5	—	ns	
Data Output Enable Time Reference to WE	t _{OW}	—	25	—	30	—	30	—	30	ns	
Output Buffer Turn-off Delay	t _{OFF}	0	20	0	20	0	20	0	20	ns	
Transition Time	t _T	3	50	3	50	3	50	3	50	ns	3
RAS Precharge	t _{RP}	50	—	50	—	60	—	80	—	ns	
RAS Pulse Width	t _{RAS}	60	10,000	70	10,000	80	10,000	100	10,000	ns	
RAS Pulse Width (Static Column Mode Cycle Only)	t _{RASC}	60	100,000	70	100,000	80	100,000	100	100,000	ns	
RAS Hold Time	t _{RSH}	15	—	20	—	20	—	25	—	ns	
CS Precharge Time (Static Column Mode)	t _{CP}	10	—	10	—	10	—	10	—	ns	
CS Pulse Width	t _{CS}	15	10,000	20	10,000	20	10,000	25	10,000	ns	
CS Pulse Width (Static Column Mode Cycle Only)	t _{CSC}	15	100,000	20	100,000	20	100,000	25	100,000	ns	
CS Hold Time	t _{CSH}	60	—	70	—	80	—	100	—	ns	
RAS to CS Delay Time	t _{RCD}	20	45	20	50	20	60	25	75	ns	5
RAS to Column Address Delay Time	t _{RAD}	15	30	15	35	15	40	20	50	ns	6
CS to RAS Precharge Time	t _{CRP}	5	—	5	—	5	—	5	—	ns	
Row Address Set-up Time	t _{ASR}	0	—	0	—	0	—	0	—	ns	

AC Characteristics (2/3)

(V_{CC} = 5V ± 10%, T_a = 0 to 70°C) Note 1, 2, 3

Parameter	Symbol	MSM 511002B-60		MSM 511002B-70		MSM 511002B-80		MSM 511002B-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Row Address Hold Time	t _{RAH}	10	—	10	—	10	—	10	—	ms	
Column Address Set-up Time	t _{ASC}	0	—	0	—	0	—	0	—	ns	
Column Address Hold Time	t _{CAH}	15	—	15	—	15	—	15	—	ns	
Column Address to $\overline{\text{RAS}}$ Lead Time	t _{RAL}	30	—	35	—	40	—	50	—	ns	
Column Address Hold Time Reference to $\overline{\text{RAS}}$ (WRITE CYCLE)	t _{AWR}	50	—	55	—	60	—	75	—	ns	
Column Address Hold Time Reference to $\overline{\text{RAS}}$	t _{AR}	75	—	85	—	95	—	115	—	ns	
Column Address Hold Time Reference to $\overline{\text{RAS}}$ Precharge	t _{AH}	10	—	10	—	10	—	10	—	ns	
Column Address Hold Time Reference to $\overline{\text{WE}}$	t _{AHLW}	60	—	65	—	75	—	95	—	ns	
Last Write to Column Address Delay	t _{LWAD}	20	30	20	30	20	35	25	45	ns	7
Read Command Set-up Time	t _{RCS}	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time Reference to $\overline{\text{CS}}$	t _{RCH}	0	—	0	—	0	—	0	—	ns	9
Write Command Hold Time from $\overline{\text{RAS}}$	t _{WCR}	50	—	55	—	60	—	75	—	ns	
Write Command Set-up Time	t _{WCS}	0	—	0	—	0	—	0	—	ns	8
Write Command Pulse Width	t _{WP}	10	—	15	—	15	—	20	—	ns	
Write Invalid Time	t _{WI}	10	—	10	—	10	—	10	—	ns	
Write Command Hold Time ($\overline{\text{DOUT}}$ Disable)	t _{WCH}	10	—	15	—	15	—	20	—	ns	8
Data-in Hold Time from $\overline{\text{RAS}}$	t _{DHR}	50	—	55	—	60	—	75	—	ns	
Data Output Hold Time Reference to $\overline{\text{WE}}$	t _{WOH}	0	—	0	—	0	—	0	—	ns	
Write Command to $\overline{\text{RAS}}$ Lead Time	t _{RWL}	15	—	20	—	20	—	25	—	ns	
Write Command to $\overline{\text{CS}}$ Lead Time	t _{CWL}	15	—	20	—	20	—	25	—	ns	
Data-in Set-up Time	t _{DS}	0	—	0	—	0	—	0	—	ns	10
Data-in Hold Time	t _{DH}	15	—	15	—	15	—	20	—	ns	10
$\overline{\text{CS}}$ to $\overline{\text{WE}}$ Delay	t _{CWD}	15	—	20	—	20	—	25	—	ns	8
$\overline{\text{RAS}}$ to $\overline{\text{WE}}$ Delay	t _{RWD}	60	—	70	—	80	—	100	—	ns	8
Column Address to $\overline{\text{WE}}$ Delay Time	t _{AWD}	30	—	35	—	40	—	50	—	ns	8
$\overline{\text{RAS}}$ to Second $\overline{\text{WE}}$ Delay	t _{RSWD}	75	—	85	—	95	—	115	—	ns	

AC Characteristics (3/3)

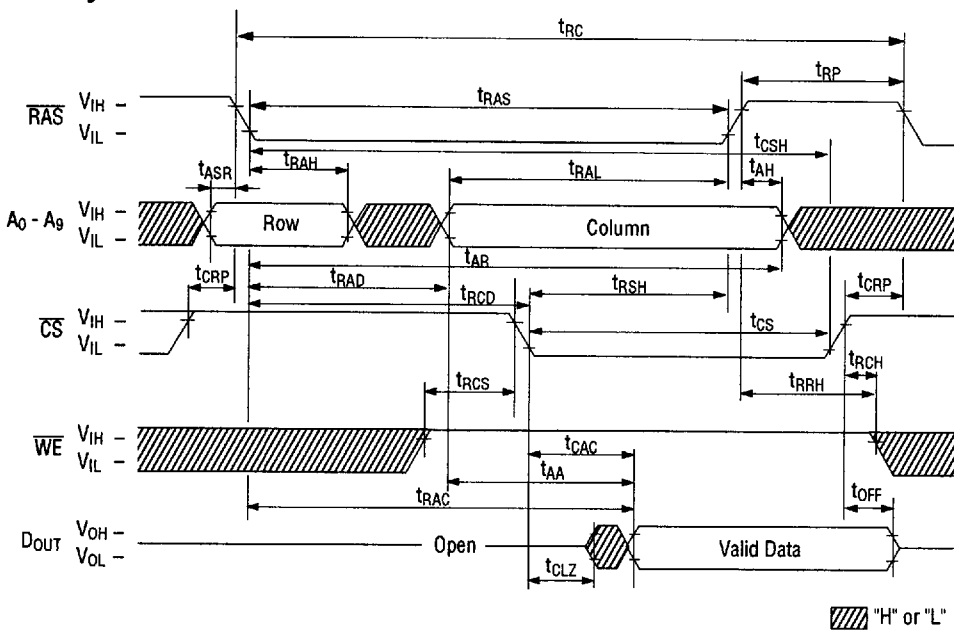
(V_{CC} = 5V ± 10%, T_a = 0 to 70°C) Note 1, 2, 3

Parameter	Symbol	MSM 511002B-60		MSM 511002B-70		MSM 511002B-80		MSM 511002B-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Read Command Hold Time Reference to $\overline{\text{RAS}}$	t _{RRH}	0	—	0	—	0	—	0	—	ns	9
$\overline{\text{RAS}}$ to $\overline{\text{CS}}$ Set-up Time ($\overline{\text{CS}}$ Before $\overline{\text{RAS}}$)	t _{CSR}	10	—	10	—	10	—	10	—	ns	
$\overline{\text{RAS}}$ to $\overline{\text{CS}}$ Hold Time ($\overline{\text{CS}}$ Before $\overline{\text{RAS}}$)	t _{CHR}	30	—	30	—	30	—	30	—	ns	
$\overline{\text{CS}}$ Active Delay from $\overline{\text{RAS}}$ Precharge	t _{RPC}	10	—	10	—	10	—	10	—	ns	
$\overline{\text{CS}}$ Precharge Time (Refresh Counter Test)	t _{CPT}	40	—	40	—	40	—	50	—	ns	
$\overline{\text{CS}}$ Precharge Time	t _{CPN}	10	—	10	—	10	—	15	—	ns	

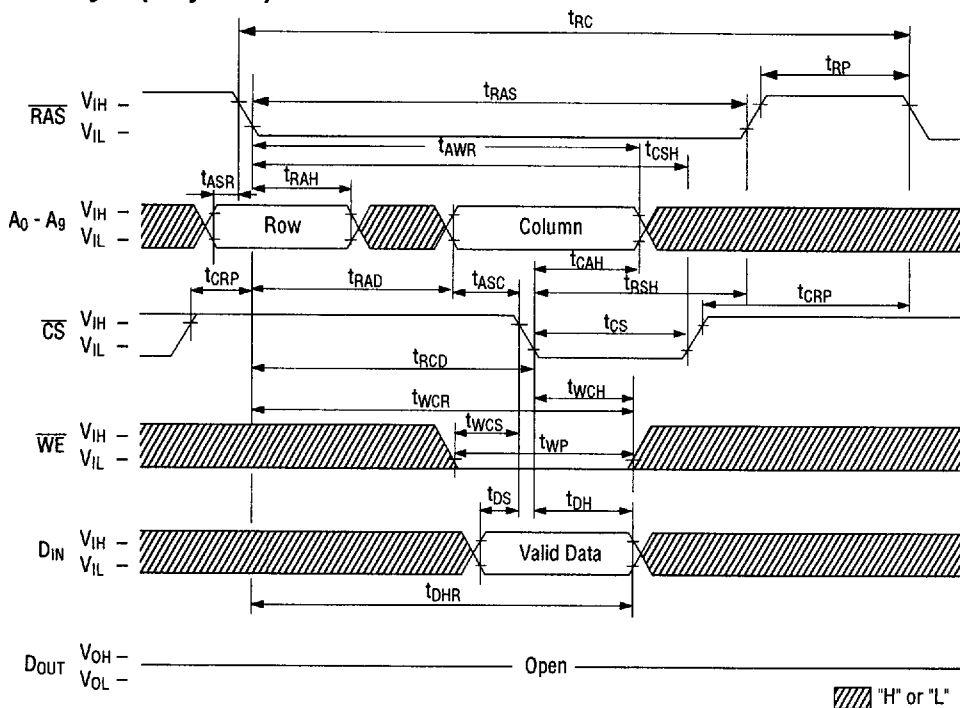
- Notes:
1. An initial pause of 100 μ s is required after power-up followed by any 8 $\overline{\text{RAS}}$ cycles (Example: $\overline{\text{RAS}}$ -only) before proper device operation is achieved.
 2. The AC characteristics assume $t_f = 5\text{ns}$.
 3. V_{IH} (Min.) and V_{IL} (Max.) are reference levels of input signals for timing measurement. Transition times (t_T) are measured between V_{IH} and V_{IL} .
 4. Measured with a load circuit equivalent to 2TTL loads and 100pF.
 5. Operation within the t_{RCD} (Max.) limit insures that t_{RCC} (Max.) can be met. t_{RCD} (Max.) is specified as a reference point only; if t_{RCD} is greater than the specified t_{RCD} (Max.) limit, access time is controlled exclusively by t_{CAC} .
 6. Operation within the t_{RAD} (Max.) limit insures that t_{RAC} (Max.) can be met. t_{RAD} (Max.) is specified as a reference point only; if t_{RAD} is greater than the specified t_{RAD} (Max.) limit, then access time is controlled exclusively by t_{AA} .
 7. Operation within the t_{LWAD} (Max.) limit insures that t_{ALW} (Max.) can be met. t_{LWAD} (Max.) is specified as a reference point only; if t_{LWAD} is greater than the specified t_{LWAD} (Max.) limit, access time is controlled exclusively by t_{AA} .
 8. t_{WCS} , t_{WH} , t_{CWD} , t_{RWD} and t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only; if $t_{WCS} \geq t_{WCS}(\text{Min.})$ and $t_{WH} \geq t_{WH}(\text{Min.})$, the cycle is an Early Write cycle and the data out pin remains open circuit (high impedance) throughout the entire cycle; if $t_{CWD} \geq t_{CWD}(\text{Min.})$, $t_{RWD} \geq t_{RWD}(\text{Min.})$ and $t_{AWD} \geq t_{AWD}(\text{Min.})$, the cycle is a read modify write cycle and the data out contains data read from the selected cell; if neither of the above sets of conditions is satisfied the condition of the data out (at access time) is indeterminate.
 9. Either t_{RRH} or t_{RCH} must be satisfied for a read cycle.
 10. These parameters are referenced to $\overline{\text{CS}}$ leading edge in an early write cycle and to $\overline{\text{WE}}$ leading edge in a read modify write cycle.

TIMING WAVEFORM

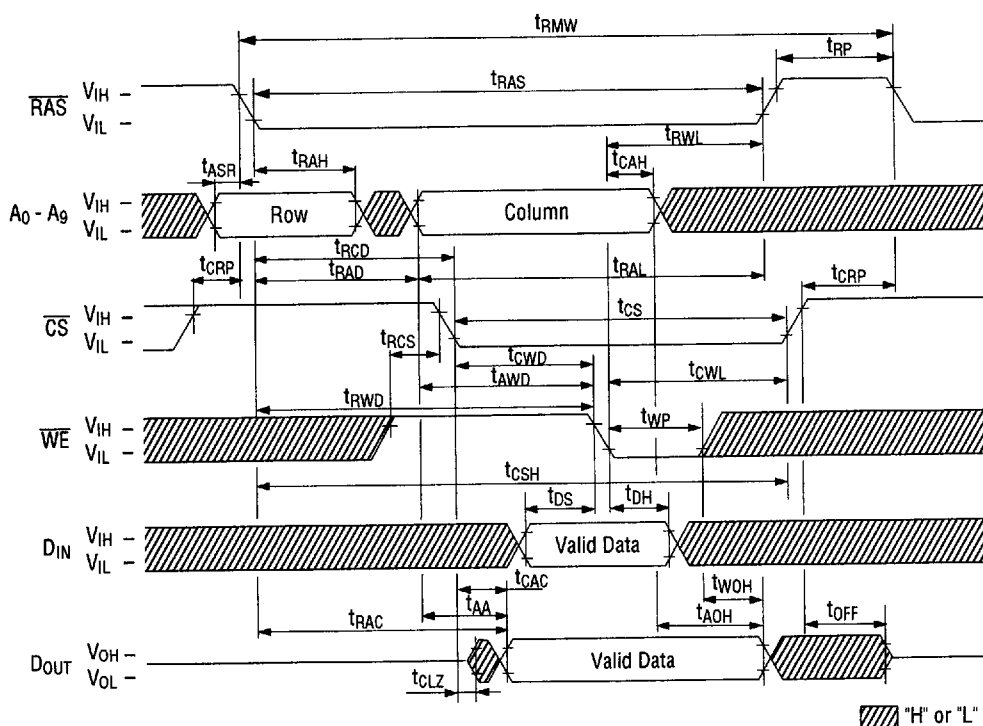
Read Cycle



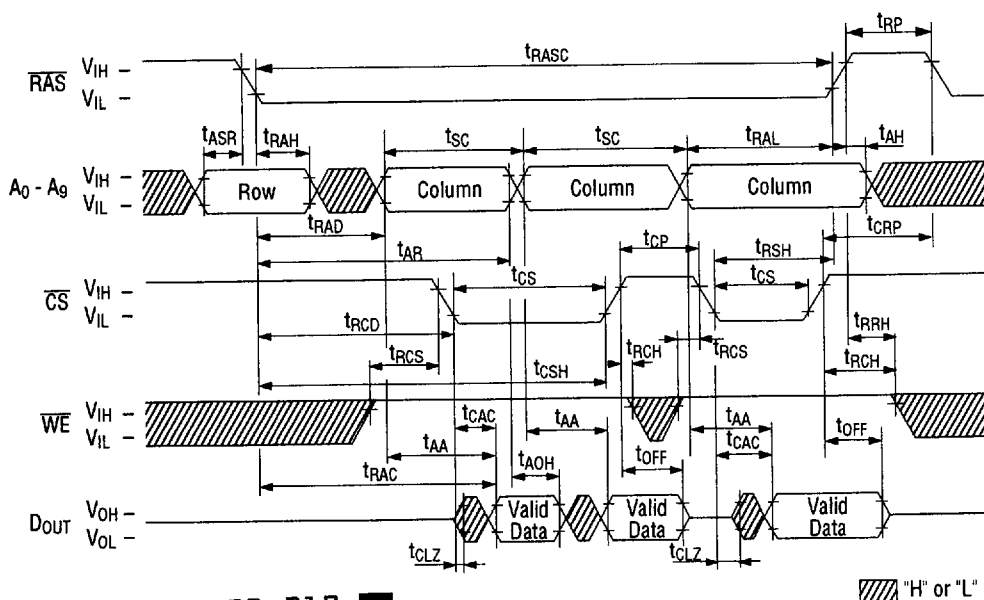
Write Cycle (Early Write)



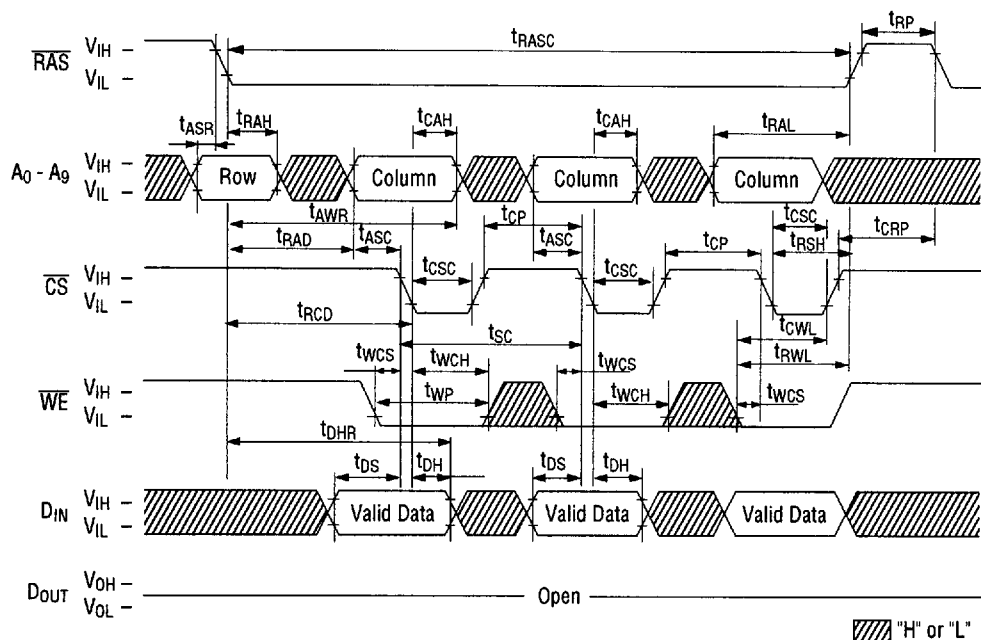
Read Modify Write Cycle



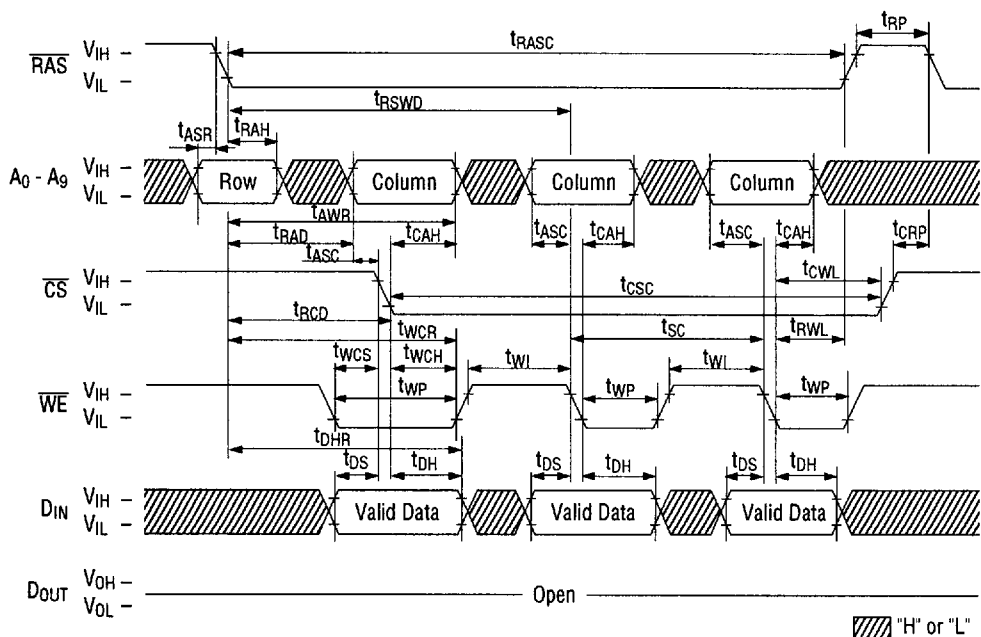
Static Column Mode Read Cycle



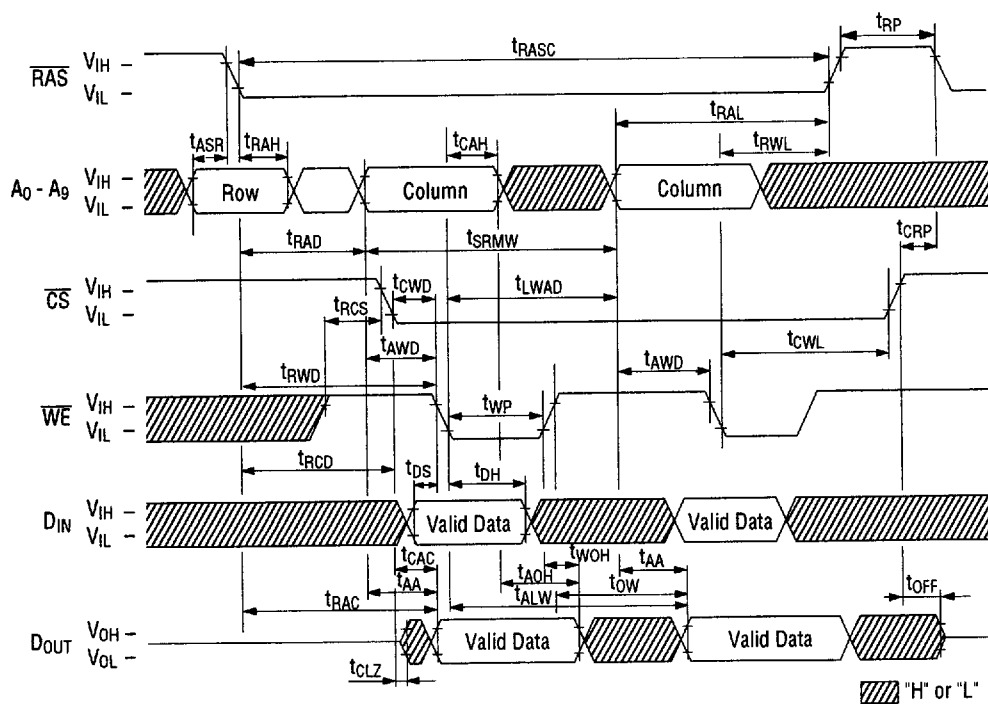
Static Column Mode Write Cycle (Early Write)



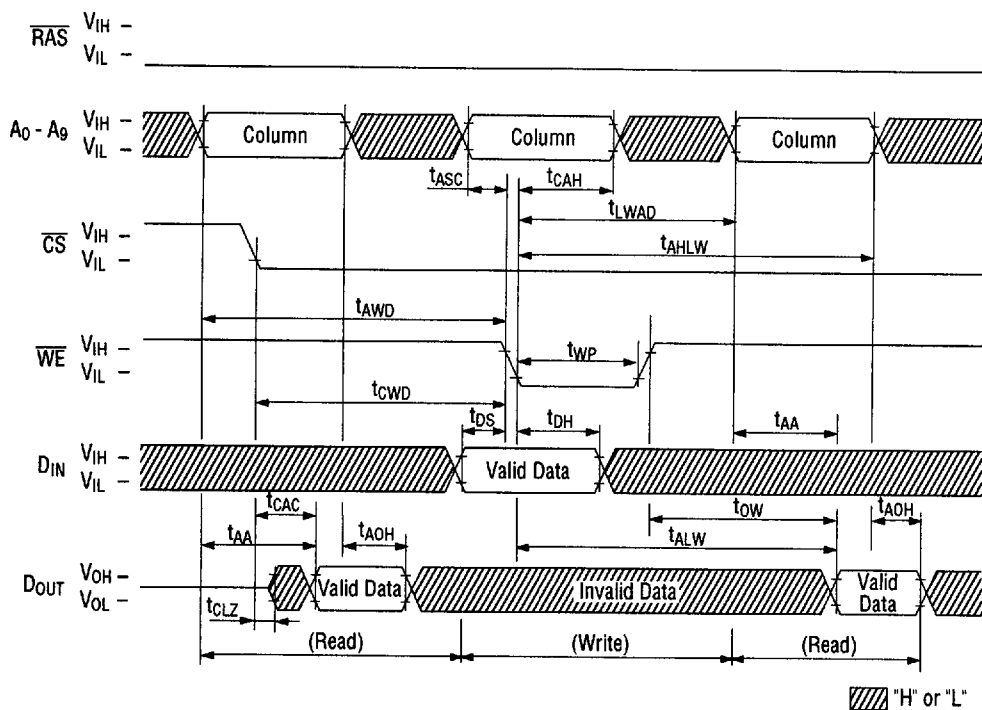
Static Column Mode Write Cycle (Early Write)

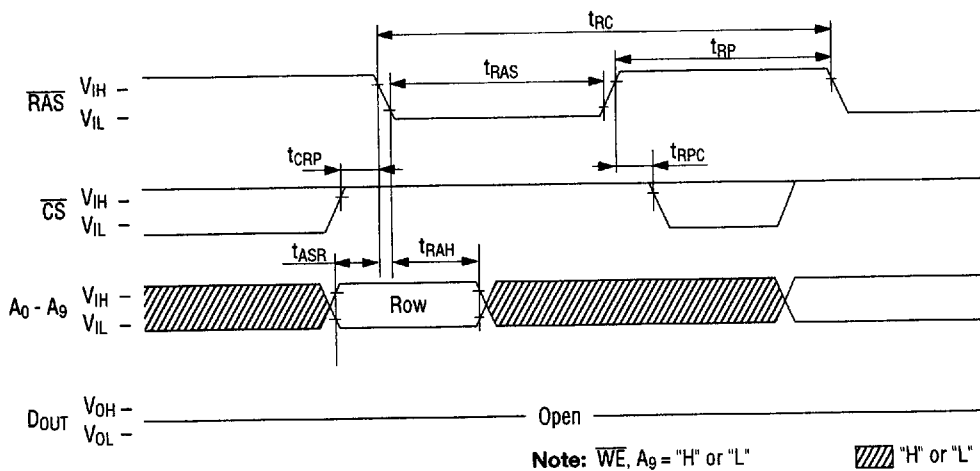
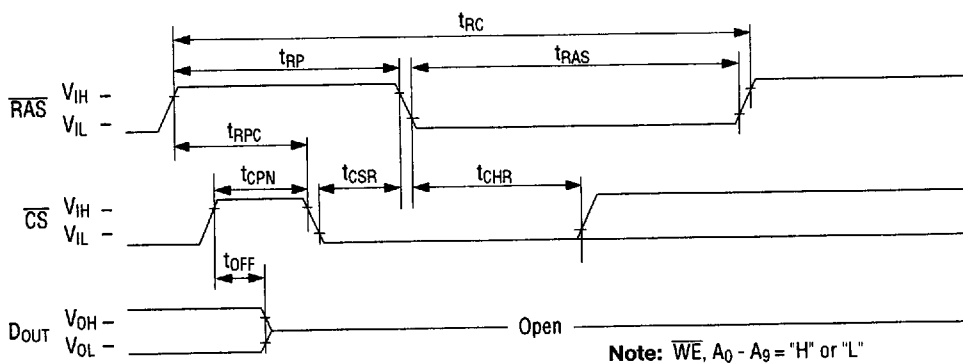


Static Column Mode Read Modify Write Cycle

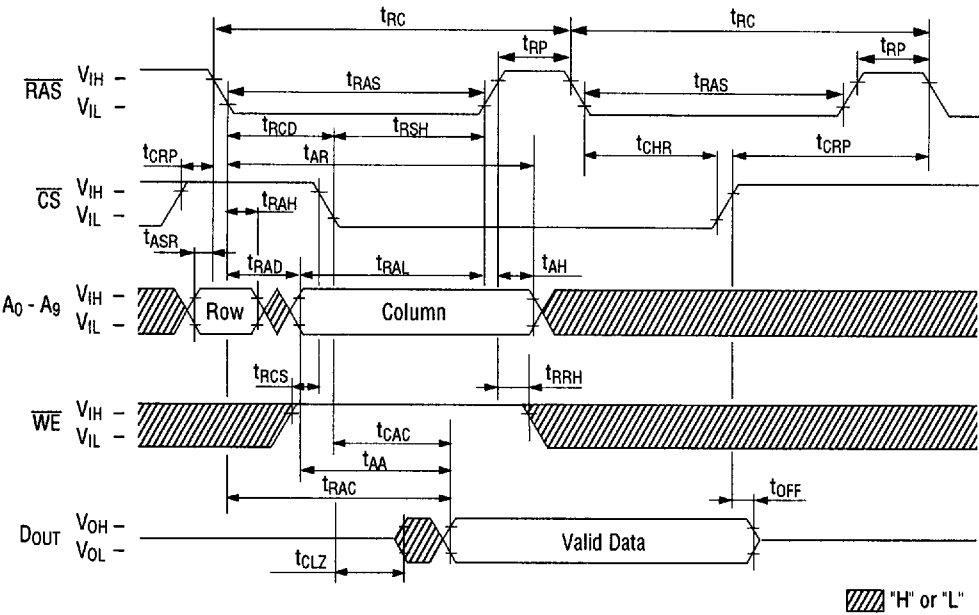


Static Column Mode Read/Write Mixed Cycle

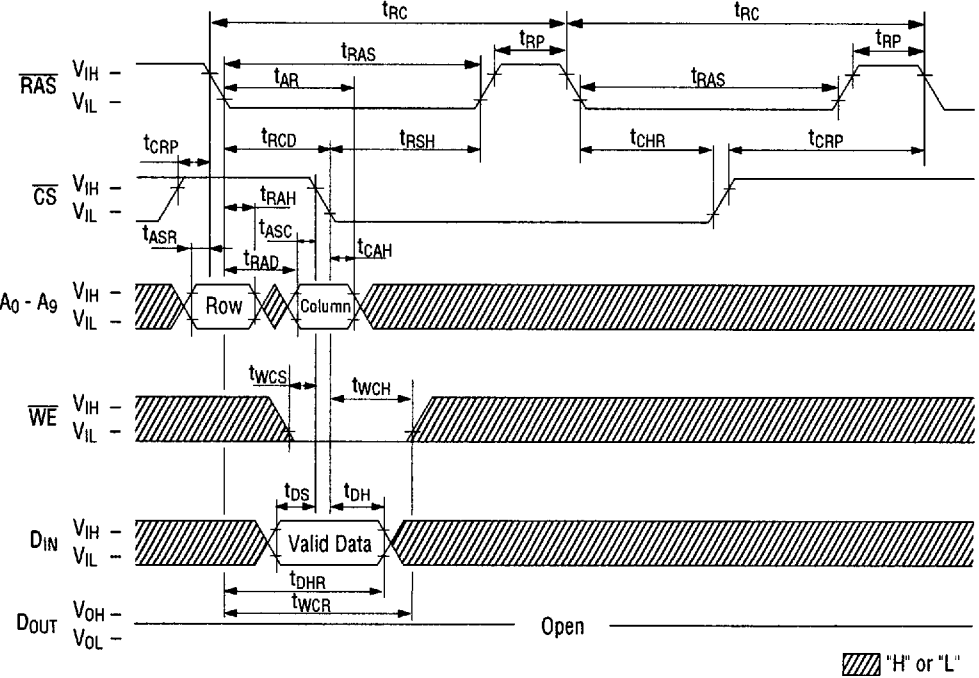


RAS-only Refresh Cycle **$\overline{\text{CS}}$ Before RAS Auto-refresh Cycle**

Hidden Refresh Read Cycle



Hidden Refresh Write Cycle



CS Before RAS Refresh Counter Test Cycle